

APPENDIX II

PRESSURE TRANSDUCER AGING REPORT

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GENERAL ELECTRIC

SPACE DIVISION
PHILADELPHIA

PROGRAM INFORMATION REQUEST / RELEASE

CLASS. LTR.	OPERATION	PROGRAM	SEQUENCE NO.	REV. LTR.
U	1B50	CAMS	235	
PIR NO.				
*USE "C" FOR CLASSIFIED AND "U" FOR UNCLASSIFIED				

TO Jerry D. Fuller, Project Engineer Analyzer Programs Room U-3035 - Ext. 2518	TO E.J. Savitsky, Manager Analyzer Programs Room U-3035 - Ext. 2956
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DATE SENT 10/2/80	DATE INFO. REQUIRED	PROJECT AND REQ. NO. 2F3	REFERENCE DIR. NO.
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SUBJECT
ACCELERATED LIFE TEST REPORT - CEC-1000 PRESSURE TRANSDUCER

INFORMATION REQUESTED/RELEASED

The aging procedure defined in PIR 1B90-CAMS-205 was completed on CEC Pressure Transducer Part Number 1000-173, S/N 4240.

RESULTS

- Overall worse case change in performance occurred at 350°F and was a zero shift of -.413% of Full Scale.
- Unit aging is unnecessary since pressure transducer contains no age sensitive materials.
- Aging test served to increase confidence in component reliability.

SPECIMEN

The specimen included CEC Transducer S/N 4240, (see Attachment 1) mating connector P/N 17020 and ~50 feet of cable fabricated from Raychem Spec. 44 twisted shielded pair.

DISCUSSION

Log of key test activity is summarized in Table 1 and followed by a brief description of each.

TABLE 1

TEST LOG

ACTIVITY	LOCATION	DATE
Acceptance Test Procedure Dated 7/7/77	CEC	4/9/79
Accelerated Life Environment	GE-SD	8/ 2/79 to 8/17/79
Radiation Exposure	Isomedix, Inc.	9/79
Seismic Event	Acton, Acton, Mass.	10/79
Acceptance Test Procedure Dated 7/7/77	CEC	3/2/80

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J. Ashly (CEC)

500-17-18-0

COPIES FOR	RETENTION REQUIREMENTS
<input type="checkbox"/> 1 MO.	<input type="checkbox"/> 3 MOS.
<input type="checkbox"/> 3 MOS.	<input type="checkbox"/> 6 MOS.
<input type="checkbox"/> 6 MOS.	<input type="checkbox"/> 12 MOS.
<input type="checkbox"/> 12 MOS.	<input type="checkbox"/> 18 MOS.
<input type="checkbox"/> 24 MOS.	<input type="checkbox"/> 36 MOS.
<input type="checkbox"/> 48 MOS.	<input type="checkbox"/> 72 MOS.
<input type="checkbox"/> 96 MOS.	<input type="checkbox"/> 144 MOS.
<input type="checkbox"/> 192 MOS.	<input type="checkbox"/> 384 MOS.
<input type="checkbox"/> 384 MOS.	<input type="checkbox"/> 768 MOS.
<input type="checkbox"/> 768 MOS.	<input type="checkbox"/> 1536 MOS.
<input type="checkbox"/> 1536 MOS.	<input type="checkbox"/> 3072 MOS.
<input type="checkbox"/> 3072 MOS.	<input type="checkbox"/> 6144 MOS.
<input type="checkbox"/> 6144 MOS.	<input type="checkbox"/> 12288 MOS.
<input type="checkbox"/> 12288 MOS.	<input type="checkbox"/> 24576 MOS.
<input type="checkbox"/> 24576 MOS.	<input type="checkbox"/> 49152 MOS.
<input type="checkbox"/> 49152 MOS.	<input type="checkbox"/> 98304 MOS.
<input type="checkbox"/> 98304 MOS.	<input type="checkbox"/> 196608 MOS.
<input type="checkbox"/> 196608 MOS.	<input type="checkbox"/> 393216 MOS.
<input type="checkbox"/> 393216 MOS.	<input type="checkbox"/> 786432 MOS.
<input type="checkbox"/> 786432 MOS.	<input type="checkbox"/> 1572864 MOS.
<input type="checkbox"/> 1572864 MOS.	<input type="checkbox"/> 3145728 MOS.
<input type="checkbox"/> 3145728 MOS.	<input type="checkbox"/> 6291456 MOS.
<input type="checkbox"/> 6291456 MOS.	<input type="checkbox"/> 12582912 MOS.
<input type="checkbox"/> 12582912 MOS.	<input type="checkbox"/> 25165824 MOS.
<input type="checkbox"/> 25165824 MOS.	<input type="checkbox"/> 50331648 MOS.
<input type="checkbox"/> 50331648 MOS.	<input type="checkbox"/> 100663296 MOS.
<input type="checkbox"/> 100663296 MOS.	<input type="checkbox"/> 201326592 MOS.
<input type="checkbox"/> 201326592 MOS.	<input type="checkbox"/> 402653184 MOS.
<input type="checkbox"/> 402653184 MOS.	<input type="checkbox"/> 805306368 MOS.
<input type="checkbox"/> 805306368 MOS.	<input type="checkbox"/> 1610612736 MOS.
<input type="checkbox"/> 1610612736 MOS.	<input type="checkbox"/> 3221225472 MOS.
<input type="checkbox"/> 3221225472 MOS.	<input type="checkbox"/> 6442450944 MOS.
<input type="checkbox"/> 6442450944 MOS.	<input type="checkbox"/> 12884901888 MOS.
<input type="checkbox"/> 12884901888 MOS.	<input type="checkbox"/> 25769803776 MOS.
<input type="checkbox"/> 25769803776 MOS.	<input type="checkbox"/> 51539607552 MOS.
<input type="checkbox"/> 51539607552 MOS.	<input type="checkbox"/> 103079215104 MOS.
<input type="checkbox"/> 103079215104 MOS.	<input type="checkbox"/> 206158430208 MOS.
<input type="checkbox"/> 206158430208 MOS.	<input type="checkbox"/> 412316860416 MOS.
<input type="checkbox"/> 412316860416 MOS.	<input type="checkbox"/> 824633720832 MOS.
<input type="checkbox"/> 824633720832 MOS.	<input type="checkbox"/> 1649267441664 MOS.
<input type="checkbox"/> 1649267441664 MOS.	<input type="checkbox"/> 3298534883328 MOS.
<input type="checkbox"/> 3298534883328 MOS.	<input type="checkbox"/> 6597069766656 MOS.
<input type="checkbox"/> 6597069766656 MOS.	<input type="checkbox"/> 13194139533312 MOS.
<input type="checkbox"/> 13194139533312 MOS.	<input type="checkbox"/> 26388279066624 MOS.
<input type="checkbox"/> 26388279066624 MOS.	<input type="checkbox"/> 52776558133248 MOS.
<input type="checkbox"/> 52776558133248 MOS.	<input type="checkbox"/> 105553116266496 MOS.
<input type="checkbox"/> 105553116266496 MOS.	<input type="checkbox"/> 211106232532992 MOS.
<input type="checkbox"/> 211106232532992 MOS.	<input type="checkbox"/> 422212465065984 MOS.
<input type="checkbox"/> 422212465065984 MOS.	<input type="checkbox"/> 844424930131968 MOS.
<input type="checkbox"/> 844424930131968 MOS.	<input type="checkbox"/> 1688849860263936 MOS.
<input type="checkbox"/> 1688849860263936 MOS.	<input type="checkbox"/> 3377699720527872 MOS.
<input type="checkbox"/> 3377699720527872 MOS.	<input type="checkbox"/> 6755399441055744 MOS.
<input type="checkbox"/> 6755399441055744 MOS.	<input type="checkbox"/> 13510798882111488 MOS.
<input type="checkbox"/> 13510798882111488 MOS.	<input type="checkbox"/> 27021597764222976 MOS.
<input type="checkbox"/> 27021597764222976 MOS.	<input type="checkbox"/> 54043195528445952 MOS.
<input type="checkbox"/> 54043195528445952 MOS.	<input type="checkbox"/> 108086391056891904 MOS.
<input type="checkbox"/> 108086391056891904 MOS.	<input type="checkbox"/> 216172782113783808 MOS.
<input type="checkbox"/> 216172782113783808 MOS.	<input type="checkbox"/> 432345564227567616 MOS.
<input type="checkbox"/> 432345564227567616 MOS.	<input type="checkbox"/> 864691128455135232 MOS.
<input type="checkbox"/> 864691128455135232 MOS.	<input type="checkbox"/> 1729382256910270464 MOS.
<input type="checkbox"/> 1729382256910270464 MOS.	<input type="checkbox"/> 3458764513820540928 MOS.
<input type="checkbox"/> 3458764513820540928 MOS.	<input type="checkbox"/> 6917529027641081856 MOS.
<input type="checkbox"/> 6917529027641081856 MOS.	<input type="checkbox"/> 13835058055282163712 MOS.
<input type="checkbox"/> 13835058055282163712 MOS.	<input type="checkbox"/> 27670116110564327424 MOS.
<input type="checkbox"/> 27670116110564327424 MOS.	<input type="checkbox"/> 55340232221128654848 MOS.
<input type="checkbox"/> 55340232221128654848 MOS.	<input type="checkbox"/> 110680464442257309696 MOS.
<input type="checkbox"/> 110680464442257309696 MOS.	<input type="checkbox"/> 221360928884514619392 MOS.
<input type="checkbox"/> 221360928884514619392 MOS.	<input type="checkbox"/> 442721857769029238784 MOS.
<input type="checkbox"/> 442721857769029238784 MOS.	<input type="checkbox"/> 885443715538058477568 MOS.
<input type="checkbox"/> 885443715538058477568 MOS.	<input type="checkbox"/> 1770887431076116955136 MOS.
<input type="checkbox"/> 1770887431076116955136 MOS.	<input type="checkbox"/> 3541774862152233910272 MOS.
<input type="checkbox"/> 3541774862152233910272 MOS.	<input type="checkbox"/> 7083549724304467820544 MOS.
<input type="checkbox"/> 7083549724304467820544 MOS.	<input type="checkbox"/> 14167099448608935641088 MOS.
<input type="checkbox"/> 14167099448608935641088 MOS.	<input type="checkbox"/> 28334198897217871282176 MOS.
<input type="checkbox"/> 28334198897217871282176 MOS.	<input type="checkbox"/> 56668397794435742564352 MOS.
<input type="checkbox"/> 56668397794435742564352 MOS.	<input type="checkbox"/> 113336795588871485128704 MOS.
<input type="checkbox"/> 113336795588871485128704 MOS.	<input type="checkbox"/> 226673591177742970257408 MOS.
<input type="checkbox"/> 226673591177742970257408 MOS.	<input type="checkbox"/> 453347182355485940514816 MOS.
<input type="checkbox"/> 453347182355485940514816 MOS.	<input type="checkbox"/> 906694364710971881029632 MOS.
<input type="checkbox"/> 906694364710971881029632 MOS.	<input type="checkbox"/> 1813388729421943762059264 MOS.
<input type="checkbox"/> 1813388729421943762059264 MOS.	<input type="checkbox"/> 3626777458843887524118528 MOS.
<input type="checkbox"/> 3626777458843887524118528 MOS.	<input type="checkbox"/> 7253554917687775048237056 MOS.
<input type="checkbox"/> 7253554917687775048237056 MOS.	<input type="checkbox"/> 14507109835375550096474112 MOS.
<input type="checkbox"/> 14507109835375550096474112 MOS.	<input type="checkbox"/> 29014219670751100192948224 MOS.
<input type="checkbox"/> 29014219670751100192948224 MOS.	<input type="checkbox"/> 58028439341502200385896448 MOS.
<input type="checkbox"/> 58028439341502200385896448 MOS.	<input type="checkbox"/> 116056878683004400771792896 MOS.
<input type="checkbox"/> 116056878683004400771792896 MOS.	<input type="checkbox"/> 232113757366008801543585792 MOS.
<input type="checkbox"/> 232113757366008801543585792 MOS.	<input type="checkbox"/> 464227514732017603087171584 MOS.
<input type="checkbox"/> 464227514732017603087171584 MOS.	<input type="checkbox"/> 928455029464035206174343168 MOS.
<input type="checkbox"/> 928455029464035206174343168 MOS.	<input type="checkbox"/> 1856910058928070412348686336 MOS.
<input type="checkbox"/> 1856910058928070412348686336 MOS.	<input type="checkbox"/> 3713820117856140824697372672 MOS.
<input type="checkbox"/> 3713820117856140824697372672 MOS.	<input type="checkbox"/> 7427640235712281649394745344 MOS.
<input type="checkbox"/> 7427640235712281649394745344 MOS.	<input type="checkbox"/> 14855280471424563298789490688 MOS.
<input type="checkbox"/> 14855280471424563298789490688 MOS.	<input type="checkbox"/> 29710560942849126597578981376 MOS.
<input type="checkbox"/> 29710560942849126597578981376 MOS.	<input type="checkbox"/> 59421121885698253195157962752 MOS.
<input type="checkbox"/> 59421121885698253195157962752 MOS.	<input type="checkbox"/> 118842243771396506390315925504 MOS.
<input type="checkbox"/> 118842243771396506390315925504 MOS.	<input type="checkbox"/> 237684487542793012780631851008 MOS.
<input type="checkbox"/> 237684487542793012780631851008 MOS.	<input type="checkbox"/> 475368975085586025561263702016 MOS.
<input type="checkbox"/> 475368975085586025561263702016 MOS.	<input type="checkbox"/> 950737950171172051122527404032 MOS.
<input type="checkbox"/> 950737950171172051122527404032 MOS.	<input type="checkbox"/> 1901475900342344102245054808064 MOS.
<input type="checkbox"/> 1901475900342344102245054808064 MOS.	<input type="checkbox"/> 3802951800684688204490109616128 MOS.
<input type="checkbox"/> 3802951800684688204490109616128 MOS.	<input type="checkbox"/> 7605903601369376408980219232256 MOS.
<input type="checkbox"/> 7605903601369376408980219232256 MOS.	<input type="checkbox"/> 15211807202738752817960438464512 MOS.
<input type="checkbox"/> 15211807202738752817960438464512 MOS.	<input type="checkbox"/> 30423614405477505635920876929024 MOS.
<input type="checkbox"/> 30423614405477505635920876929024 MOS.	<input type="checkbox"/> 60847228810955011271841753858048 MOS.
<input type="checkbox"/> 60847228810955011271841753858048 MOS.	<input type="checkbox"/> 121694457621910022543683507716096 MOS.
<input type="checkbox"/> 121694457621910022543683507716096 MOS.	<input type="checkbox"/> 243388915243820045087367015432192 MOS.
<input type="checkbox"/> 243388915243820045087367015432192 MOS.	<input type="checkbox"/> 486777830487640090174734030864384 MOS.
<input type="checkbox"/> 486777830487640090174734030864384 MOS.	<input type="checkbox"/> 973555660975280180349468061728768 MOS.
<input type="checkbox"/> 973555660975280180349468061728768 MOS.	<input type="checkbox"/> 1947111321950560360698936123457536 MOS.
<input type="checkbox"/> 1947111321950560360698936123457536 MOS.	<input type="checkbox"/> 3894222643901120721397872246915072 MOS.
<input type="checkbox"/> 3894222643901120721397872246915072 MOS.	<input type="checkbox"/> 7788445287802241442795744493830144 MOS.
<input type="checkbox"/> 7788445287802241442795744493830144 MOS.	<input type="checkbox"/> 15576890575604482885591488987660288 MOS.
<input type="checkbox"/> 15576890575604482885591488987660288 MOS.	<input type="checkbox"/> 31153781151208965771182977975320576 MOS.
<input type="checkbox"/> 31153781151208965771182977975320576 MOS.	<input type="checkbox"/> 62307562302417931542365955950641152 MOS.
<input type="checkbox"/> 62307562302417931542365955950641152 MOS.	<input type="checkbox"/> 124615124604835863084731911901282304 MOS.
<input type="checkbox"/> 124615124604835863084731911901282304 MOS.	<input type="checkbox"/> 249230249209671726169463823802564608 MOS.
<input type="checkbox"/> 249230249209671726169463823802564608 MOS.	<input type="checkbox"/> 498460498419343452338927647605129216 MOS.
<input type="checkbox"/> 498460498419343452338927647605129216 MOS.	<input type="checkbox"/> 996920996838686904677855295210258432 MOS.
<input type="checkbox"/> 996920996838686904677855295210258432 MOS.	<input type="checkbox"/> 1993841993677373809355710590420516864 MOS.
<input type="checkbox"/> 1993841993677373809355710590420516864 MOS.	<input type="checkbox"/> 3987683987354747618711421180841033728 MOS.
<input type="checkbox"/> 3987683987354747618711421180841033728 MOS.	<input type="checkbox"/> 7975367974709495237422842361682067456 MOS.
<input type="checkbox"/> 7975367974709495237422842361682067456 MOS.	<input type="checkbox"/> 15950735949418990474845684723364134912 MOS.
<input type="checkbox"/> 15950735949418990474845684723364134912 MOS.	<input type="checkbox"/> 31901471898837980949691369446728269824 MOS.
<input type="checkbox"/> 31901471898837980949691369446728269824 MOS.	<input type="checkbox"/> 63802943797675961899382738893456539648 MOS.
<input type="checkbox"/> 63802943797675961899382738893456539648 MOS.	<input type="checkbox"/> 127605887595351923798765477786913079296 MOS.
<input type="checkbox"/> 127605887595351923798765477786913079296 MOS.	<input type="checkbox"/> 255211775190703847597530955573826158592 MOS.
<input type="checkbox"/> 255211775190703847597530955573826158592 MOS.	<input type="checkbox"/> 510423550381407695195061911147652317184 MOS.
<input type="checkbox"/> 510423550381407695195061911147652317184 MOS.	<input type="checkbox"/> 1020847100762815390390123822295304634368 MOS.
<input type="checkbox"/> 1020847100762815390390123822295304634368 MOS.	<input type="checkbox"/> 2041694201525630780780247644590609268736 MOS.
<input type="checkbox"/> 2041694201525630780780247644590609268736 MOS.	<input type="checkbox"/> 4083388403051261561560495289181218537472 MOS.
<input type="checkbox"/> 4083388403051261561560495289181218537472 MOS.	<input type="checkbox"/> 8166776806102523123120990578362437074944 MOS.
<input type="checkbox"/> 8166776806102523123120990578362437074944 MOS.	<input type="checkbox"/> 16333553612205046246241981156724874149888 MOS.
<input type="checkbox"/> 16333553612205046246241981156724874149888 MOS.	<input type="checkbox"/> 32667107224410092492483962313449748299776 MOS.
<input type="checkbox"/> 32667107224410092492483962313449748299776 MOS.	<input type="checkbox"/> 65334214448820184984967924626899496599552 MOS.
<input type="checkbox"/> 65334214448820184984967924626899496599552 MOS.	<input type="checkbox"/> 130668428897640369969935849253798993199104 MOS.
<input type="checkbox"/> 130668428897640369969935849253798993199104 MOS.	<input type="checkbox"/> 261336857795280739939871698507597986398208 MOS.
<input type="checkbox"/> 261336857795280739939871698507597986398208 MOS.	<input type="checkbox"/> 522673715590561479879743397015195972796416 MOS.
<input type="checkbox"/> 522673715590561479879743397015195972796416 MOS.	<input type="checkbox"/> 1045347431181122959759486794030391945592832 MOS.
<input type="checkbox"/> 1045347431181122959759486794030391945592832 MOS.	<input type="checkbox"/> 2090694862362245919518973588060783891185664 MOS.
<input type="checkbox"/> 20906948623622459195189735880	

Pre and Post Performance Tests

Both tests were performed at CEC to the 1000-04 (173) Acceptance Test Procedure dated 7/7/77 modified to include the linearity and hysteresis run at 250°F. Results were excellent with maximum deviation occurring at 350°F as a zero shift of -.413% of full range relative to the 4/9/79 test. The CEC calibration data summary is included with this report as Attachment 2.

Accelerated Life Environment, PIR 1B90-CAMS-205

To verify the long term operation requirements, the pressure transducer was subjected to the procedure presented in Attachment 3. The aging of the pressure transducer was performed by using present state-of-the-art aging technology. This technology allows acceleration of the time/temperature aging effects artificially by increasing the temperature. The pressure transducer contains both metallic and non-metallic components. The deterioration due to aging effects on the metallic components is judged to be insignificant. The aging of the pressure transducer was therefore based on its non-metallic materials only.

It is known for many non-metallic materials, that the degradation process can be defined by a single temperature-dependent reaction that follows the Arrhenius equation:

$$- \frac{E_a}{k_B T}$$

$$k = A e \tag{1}$$

where,

k = reaction rate

A = frequency factor

E_a = activation energy

k_B = Boltzmann's Constant (8.617 x 10⁻⁵ eV/°K)

T = absolute temperature

It is further noted that, for many reactions, the activation energy can be considered to be constant over the applicable temperature range. Equation (1) can be transformed into a form which yields an acceleration factor to define a given amount of thermal degradation. The form is:

$$\frac{E_a}{k_B} \left(\frac{1}{T_1} - \frac{1}{T_2} \right) \quad (2)$$

$$t_1/t_2 = e$$

where,

t_1 = accelerated aging time at temperature T_1

t_2 = normal service time at temperature T_2

T_1 = accelerated temperature T_1 ($^{\circ}\text{K}$)

T_2 = normal service temperature T_2 ($^{\circ}\text{K}$)

Equation (2) can be used to derive the accelerated aging times for materials with known activation energies.

Normal operating temperature for the transducer is 120°F . The transducer was operated for 14 days at 300°F as presented in Table 2. From equation (2), this would age to greater than 40 years any material with an activation energy less than .81 eV. This would include most organic materials.

Aging Analysis

Table 3 describes the non-metallics in the pressure transducer. Both materials are included in the following list of materials that are considered to not have significant aging characteristics:

Silicon semi-conductors, resistors; tantalum dry electrolytic capacitors; ceramic capacitors; dry paper and plastic film capacitors; mica capacitors; glass capacitors; integrated micro-electronic devices; hybrid micro-circuits; steel, aluminum, copper, epoxy fiberglass G10, G11, or equivalent; brass, ceramic, and glass-filled diallylphthalate.

Since there are no age sensitive materials in the transducer, no aging prior to seismic is required. The temperature aging test serves as a confidence test in the pressure transducer reliability. A detailed "aging" test log is presented in Table 2.

No detectable change observed in unit performance or visual appearance.

TABLE 2
AGING TEST LOG

DATE	ACTIVITY	COMMENTS		
7/19/79	Chamber Installation	Chamber atmosphere was humidified with 15 ml H ₂ O.		
7/19 → 8/2/79	Low Temperature Operation	145°F with chamber total pressure variation of 15.8 to 17.6 PSIA.		
8/2/79	Initiate Aging Environment	Chamber was cooled to ambient and opened to allow transducer inspection. Atmosphere preparation included 1/2 atmosphere of 2% H ₂ /N ₂ and water vapor (15 ml of water). Chamber was sealed and temperature set for 300°F.		
		Temperature (°F)	Pressure (PSIA)	V _O (mv)
8-3	Aging Environment	302	53.5	18.739
8-6	"	302	55.3	19.241
8-7	"	302	53.5	18.804
8-8	"	302	49.4	17.464
8-9	"	302	49.3	17.364
8-10	"	302	49.4	17.282
8-13	"	302	47.2	16.79
8-14	"	308	49.7	17.574
8-15	"	305	49.5	17.525
8-17 (8:30)	"	305	48.6	17.259
8-17 (15:00)	"	305	48.4	17.151
8-17 (15:10)	Terminate Aging Environment	Set heat for 125°F.		
8-20 (11:45)		129	26.2	7.839
(11:50)	Terminate Test	Shut off heat, open the chamber and remove the specimen		

TABLE 3
PRESSURE TRANSDUCER - NON-METALLICS

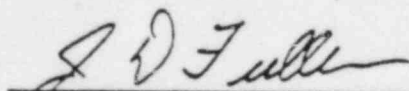
COMPONENT	MATERIAL	COMMENTS
Bridge Substrate	Silicon Oxide SiO ₂	Thin coating to which resistors are mounted.
Resistors	"Ceramicite" (CEC) Ceramic	Resistors are wire wound, nickel coated with Ceramicite which contains Al, Pb. Glass.

Radiation Exposure

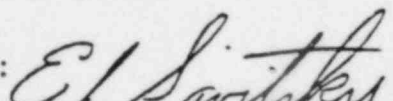
The Transducer, connector and cable assembly was delivered to Isomedix for a radiation exposure of 1.2×10^6 Rads/hr. for a total integrated dose of 3.2×10^7 Rads. Dose certification is included with this report as Attachment 4. No detectable change in unit performance or visual appearance was observed during post exposure evaluation.

Simulated Siesmic Event

The specimen was subjected to the environment described in GE-SD Procedure 250852 as part of H₂ Analyzer P/N 47E240609 System Seismic Test. Test details are presented in the '609 system Qual Test Report.


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Concurred:


Edward J. Savitsky, Manager
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/mes

SO23-508-17-18-0

CEC[®] 1000-04 Sputtered Thin Film High Temperature Pressure Transducer



- Long-Term Stability
- Highly Reliable
- High Performance
- Advanced Sensor Design
- Rugged Dual Case Isolation

Providing long-term stability and reliability, CEC Sputtered Gage Pressure Transducers are the most accurate thin film transducers available. Performance stability is $\pm 0.1\%$ for extended operation at any combination of constant pressure and temperature within the operating range. The CEC 1000-04 has a compensated temperature range of 75°F to -400°F , and an operable temperature range of -65°F to $+450^{\circ}\text{F}$. The thermal errorband performance is typically better than 0.5% within any 50°F temperature band.

Advanced techniques of sputtered film deposition create sensing elements with a maximum combined error for non-linearity, hysteresis, and non-repeatability of $\pm 0.25\%$ of the full range output.

Available in many standard ranges from 15 to 10,000 psi, the CEC 1000 Series also feature an innovative double-case isolation. The basic sputtered sensor is electron beam welded to the pressure chamber/adapter which also provides a high degree of mechanical isolation from mounting torque effects. The sputtered sensor is well isolated from external case effects since the case is welded to the pressure chamber/adapter and not in contact with any portion of the sensor.

CEC Sputtered Gage Pressure Transducers are manufactured in accordance with the program quality requirements of MIL-Q-9853A.

For further information about this pressure transducer, or special application designs, contact the nearest Bell & Howell/CEC Division Sales Office or factory in Pasadena, California.

CEC DIVISION



BELL & HOWELL

ATTACHMENT 1

SPECIFICATIONS

CEC 1000-04 Sputtered Thin Film High Temperature Pressure Transducer

Pressure Rating

Standard Ranges:	0 to 15, 25, 50, 100, 250, 500, 1000, 1500, 2000, 2500, 5000 and 10,000 psi absolute.
Proof Pressure:	0 to 100 psi and above are available in psi. 200% of rated pressure or 15,000 psi (whichever is less) will not cause changes in performance beyond specified tolerances.
Burst Pressure:	300% of rated pressure or 20,000 psi (whichever is less) will not cause rupture of the sensing element or case.

Electrical Characteristics

Excitation:	10 Vdc rated; 15 Vdc maximum.
Full Range Output:	30 mV nominal.
Residual Unbalance:	Within $\pm 5\%$ FRO.
Bridge Resistance:	300 to 500 ohms.
Combined Linearity, Hysteresis and non-repeatability:	$\pm 0.25\%$ FRO, BSL.
Insulation Resistance:	100 megohms or greater at 48 Vdc.
Connections:	6-pin Bendix PC1H-10-6P (101), or equivalent.
Shunt Calibration:	Provisions for single-arm, external shunt calibration.

Mechanical Characteristics

Pressure Chamber Material:	17-4 PH Stainless Steel.
Pressure Fitting:	7/16-20 male per MS-33656-4, MS-6879 modified per CEC standards.
Weight:	5 oz. maximum excluding mating connector.
Mounting Isolation:	Double case isolation provides assurance that the sensing element will be unaffected by external stresses.
Sensing Element:	4 active-arm bridge using sputtered elements.

Environmental Performance

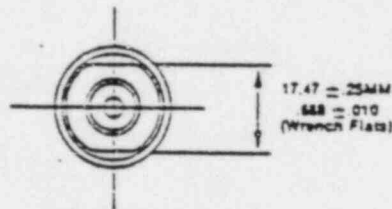
Temperature:	
Operating Range:	-65 to $+450^\circ\text{F}$.
Compensated Range:	$+75$ to $+400^\circ\text{F}$.
Thermal Zero Shift:	$\pm 0.01\%$ FRO/ $^\circ\text{F}$ over the compensated temp. range.
Thermal Sens. Shift:	$\pm 0.01\%$ FRO/ $^\circ\text{F}$ over the compensated temp. range.
Thermal Zero Stability:	0.25% FRO over the compensated temp. range.
Thermal Sens. Stability:	0.15% FRO over the compensated temp. range.
Vibration:	At 35g peak from 10 to 2000 Hz ($1/2$ " D.A. max.) the output shall not exceed 0.04% FRO/g for 15 psi units decreasing logarithmically to .003% FRO/g for 1000 psi units and above.
Natural Frequency:	50 kHz at 5000 psi, decreasing logarithmically to 5 kHz at 15 psi.
Shock:	100g, 11 msec, half sine wave without damage.
Humidity:	Per MIL-E-32720, Procedure I.

Accessories

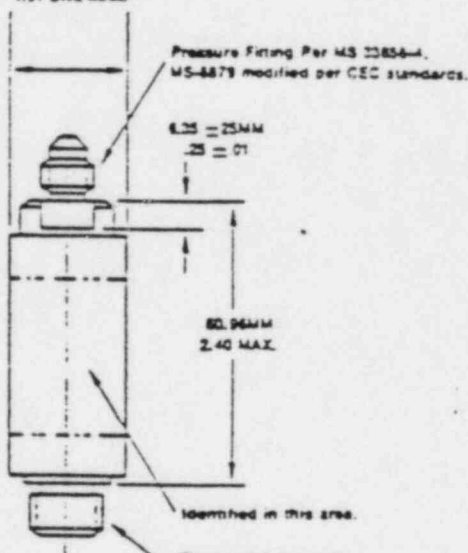
Included:	Calibration record and dust caps (2).
Optional:	Mating electrical connector Physical Sciences T106-10-65-C-P1 or equivalent, Specialty Bell & Howell PN 170200.

In keeping with Bell & Howell's policy of continuing product improvement, specifications may be changed without notice. If the performance and configuration provided herein for our standard product do not fit your exact needs please check with us regarding customized transducers. Contact us directly at the factory or through your nearest CEC Sales Office.

PIN	FUNCTION
A	- POSITIVE INPUT
B	- POSITIVE OUTPUT
C	- NEGATIVE OUTPUT
D	- NEGATIVE INPUT
E	- SHORTED TO "0"
F	- SHORTED TO "C"



± .05MM
1.01 DIA. MAX.



CEC DIVISION

360 Sierra Madre Vls, Pasadena, California 91109



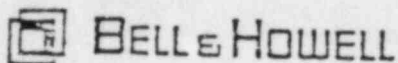
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ATTACHMENT 1

I-7

508-17-18-2



CEC DIVISION

363 SIERRA MADRE VILLA, PASADENA, CA 91109 TELEPHONE (213) 796-9381 TELEX: 87-5415

CALIBRATION DATA SUMMARY

CEC 1000-0173

S/N 4240

0-100 PSIA

Temperature	77°F		+250°F		350°F		77°F	
	*B	*A	*B	*A	*B	*A	*B	*A
Full Scale (MV)	33.389	33.504	34.100	34.260	34.149	34.188	33.368	33.486
Zero (MV)	0.262	0.353	0.855	0.924	0.732	0.594	0.253	0.350
Sens. (MV)	33.127	33.151	33.245	33.336	33.417	33.594	33.115	33.136
Insulation Resistance	10KΩ	10MΩ	10KΩ	10KΩ	5KΩ	5KΩ	5KΩ	10MΩ
ΔZero (MV)		+0.091		+0.069		-0.138		+0.097
ΔSens. (MV)		+0.024		+0.091		+0.177		+0.021
ΔZero (%FR)		+0.275		+0.208		-0.413		+0.293
ΔSens. (%FR)		+0.072		+0.274		+0.530		+0.063

LINEARITY AND HYSTERESIS RUN AT +250°F

%FS	0	20	40	60	80	100	80	60	40	20	
*B	0.855	7.473	14.115	20.769	27.430	34.099	27.438	20.776	14.122	7.482	0.
*A	0.924	7.558	14.223	20.896	27.579	34.268	27.586	20.903	14.229	7.568	0.

*B is before radiation 4/09/79

*A is after radiation 3/20/80

E. Wong

E. Wong
Sr. Product Specialist

GENERAL ELECTRIC

SPACE DIVISION
PHILADELPHIA

PROGRAM INFORMATION REQUEST / RELEASE

*CLASS. LTR.	OPERATION	PROGRAM	SEQUENCE NO.	REV. LTR.
U	1B90	CAMS	205	
*USE "C" FOR CLASSIFIED AND "U" FOR UNCLASSIFIED				

FROM	TO
J. D. Fuller, Project Engineer	F. P. Rudek, Manager - Analyzer Systems

DATE SENT	DATE INFO. REQUIRED	PROJECT AND REQ. NO.	REFERENCE DIR. NO.
7-25-79			

SUBJECT
CEC-1000-04(173) Pressure Transducer Aging Procedure

INFORMATION REQUESTED/RELEASED

The purpose of this test is to subject the transducer proposed for current configuration H₂ Analyzers to a combination of environmental conditions simulating long term operation of the transducer.

1. Initial Conditions:

- a. Place 30 ml H₂O in the chamber prior to closing.
- b. Pressurize the chamber to 15 PSIG with 2% H₂/N₂ then vent to ambient pressure. Close inlet and outlet valves.
- c. Set the temperature for 135°F ± 5°F.
- d. Record the following data for stabilized sensor performance.
 - Temperature
 - Pressure
 - Transducer Output
 - Time (Date and Time of Day)

2. Accelerated Life Temperature, Pressure Conditions:

- a. Set temperature controller to achieve a chamber temperature of 300°F⁺¹⁰⁰₋₀₀F
- b. Upon achieving a chamber temperature of 300°F, record the time and date. Vent the chamber as required to maintain a chamber pressure < 65 PSIG.
- c. Maintain the conditions established in the preceding step for 14 days and record the following information daily:
 - Temperature
 - Pressure
 - Sensor Output
 - Time

cc: J. D. Fuller
L. R. Heverly

J. E. Murphy
F. P. Rudek

PAGE NO.	RETENTION REQUIREMENTS	
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	<input type="checkbox"/> WOL.	<input type="checkbox"/> WOL.
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1 of 2

- d. Decrease the temperature setting to achieve a chamber temperature of $125 \pm 5^{\circ}\text{F}$ and maintain for 2 days. Daily record the data noted in step 2.c.
- e. Shut off the heat, open the test chamber and remove the transducer for visual inspection.

3. Radiation Exposure:

- a. Subject the transducer to a total integrated dose of 3.2×10^7 Rads at a rate of 1.2 megarads/hour.
- b. Perform CEC ATP.

J. D. Fuller
J. D. Fuller, Project Engineer
Analyzer Systems
Room #U-3035, VFSC
Extension - 2518

h

- d. Decrease the temperature setting to achieve a chamber temperature of $125 \pm 5^{\circ}\text{F}$ and maintain for 2 days. Daily record the data noted in step 2.c.
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- b. Perform CEC ATP.

J. D. Fuller
J. D. Fuller, Project Engineer
Analyzer Systems
Room #U-3035, VFSC
Extension - 2518

h



Sept. 13, 1979

J. J. Collery
General Electric Company
Space Systems
P.O. Box 8555
Philadelphia, Pa. 19101

Dear Mr. Collery:

This will summarize parameters pertinent to the irradiation of CEC XDUCER, calibration cap and cylinder, as per your purchase order A28-A10311, dated August 28, 1979.

The specimens were exposed for 37 hours at an average dose rate of 1.0 Megarads per hour, yielding a dose of 37 Megarads. The specimens were over-irradiated to account for the $\pm 3\%$ accuracy of the the dosimetry system; the reported dose is 32 Megarads.

Halfway through the exposure, the specimens were rotated 180° to give a more uniform dose distribution.

Dosimetry was performed using Harwell Red 4034 Perspex dosimeters, utilizing a Bausch and Lomb Model 710 spectrophotometer as the readout instrument. This system is calibrated directly with NBS, with the last calibration being May 30, 1979. A copy of the dosimetry correlation report is available upon request.

Irradiation was conducted in air at ambient temperature and pressure. Radiant heat from the source heated the samples somewhat, but the temperature did not exceed 130°F , as indicated by previous measurements on an oil solution in the same relative position.

Irradiation was initiated on August 31, 1979, and was completed on September 2, 1979.

Sincerely yours,

ISOMEDIX, INC.

David P. Constantine
Production Manager

DPC:vt
cc: G. Deitz

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